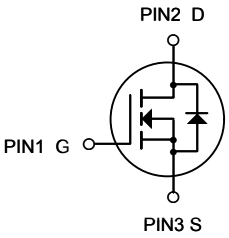
# 60N03

## N-Channel Enhancement Mode MOSFET

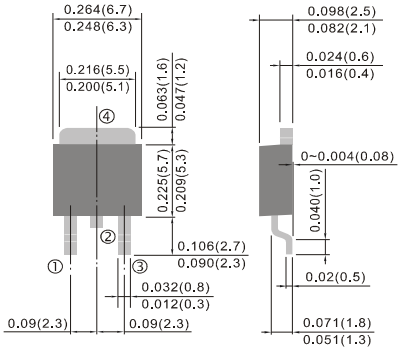
### FEATURE

- Low gate charge
- Low $C_{iss}$
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability




VOLTAGE RANGE
30Volts
CURRENT
60Amperes

TO-252




Dimensions in inches and (millimeters)

**ABSOLUTE MAXIMUM RATINGS** ($T_A$ = 25 °C, unless otherwise noted)

| Parameter | | Symbol | Limit | Unit |
|---|---|---|---|---|
| Drain-Source Voltage | | $V_{DS}$ | 30 | V |
| Gate-Source Voltage | | $V_{GS}$ | ± 20 | |
| Continuous Drain Current ($T_J$ = 175 °C) | $T_C$ = 25 °C | $I_D$ | 80 | A |
| | $T_C$ = 70 °C | | 60 | |
| | $T_A$ = 25 °C | | 25.8[b, c] | |
| | $T_A$ = 70 °C | | 22[b, c] | |
| Pulsed Drain Current | | $I_{DM}$ | 250 | |
| Avalanche Current Pulse | L = 0.1 mH | $I_{AS}$ | 39 | |
| Single Pulse Avalanche Energy | | $E_{AS}$ | 94.8 | mJ |
| Continuous Source-Drain Diode Current | $T_C$ = 25 °C | $I_S$ | 90[a, e] | A |
| | $T_A$ = 25 °C | | 3.13[b, c] | |
| Maximum Power Dissipation | $T_C$ = 25 °C | $P_D$ | 205[a] | W |
| | $T_C$ = 70 °C | | 135 | |
| | $T_A$ = 25 °C | | 3.75[b, c] | |
| | $T_A$ = 70 °C | | 2.63[b, c] | |
| Operating Junction and Storage Temperature Range | | $T_J$, $T_{stg}$ | - 55 to 175 | °C |

## THERMAL RESISTANCE RATINGS

| Parameter | | Symbol | Typ. | Max. | Unit |
|---|---|---|---|---|---|
| Maximum Junction-to-Ambient[b, d] | t ≤ 10 sec | $R_{thJA}$ | 32 | 40 | °C/W |
| Maximum Junction-to-Case | Steady State | $R_{thJC}$ | 0.5 | 0.6 | |

Notes:
a. Based on $T_C$ = 25 °C.
b. Surface mounted on 1" x 1" FR4 board.
c. t = 10 sec.
d. Maximum under steady state conditions is 90 °C/W.
e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

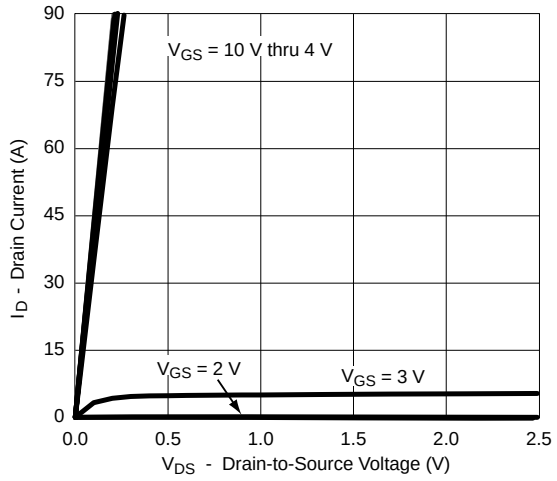
## SPECIFICATIONS ($T_J$ = 25 °C, unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| **Static** | | | | | | |
| Drain-Source Breakdown Voltage | $V_{DS}$ | $V_{GS}$ = 0 V, $I_D$ = 250 µA | 30 | | | V |
| $V_{DS}$ Temperature Coefficient | $\Delta V_{DS}/T_J$ | $I_D$ = 250 µA | | 35 | | mV/°C |
| $V_{GS(th)}$ Temperature Coefficient | $\Delta V_{GS(th)}/T_J$ | | | - 7.5 | | |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS}$ = $V_{GS}$, $I_D$ = 250 µA | 1.0 | | 2.5 | V |
| Gate-Source Leakage | $I_{GSS}$ | $V_{DS}$ = 0 V, $V_{GS}$ = ± 20 V | | | ± 100 | nA |
| Zero Gate Voltage Drain Current | $I_{DSS}$ | $V_{DS}$ = 30 V, $V_{GS}$ = 0 V | | | 1 | µA |
| | | $V_{DS}$ = 30 V, $V_{GS}$ = 0 V, $T_J$ = 55 °C | | | 10 | |
| On-State Drain Current[a] | $I_{D(on)}$ | $V_{DS}$ ≥ 5 V, $V_{GS}$ = 10 V | 90 | | | A |
| Drain-Source On-State Resistance[a] | $R_{DS(on)}$ | $V_{GS}$ = 10 V, $I_D$ = 38.8 A | | 0.005 | | Ω |
| | | $V_{GS}$ = 4.5 V, $I_D$ = 37 A | | 0.006 | | |
| Forward Transconductance[a] | $g_{fs}$ | $V_{DS}$ = 15 V, $I_D$ = 38.8 A | | 160 | | S |
| **Dynamic[b]** | | | | | | |
| Input Capacitance | $C_{iss}$ | $V_{DS}$ = 15 V, $V_{GS}$ = 0 V, f = 1 MHz | | 2201 | | pF |
| Output Capacitance | $C_{oss}$ | | | 525 | | |
| Reverse Transfer Capacitance | $C_{rss}$ | | | 270 | | |
| Total Gate Charge | $Q_g$ | $V_{DS}$ = 15 V, $V_{GS}$ = 10 V, $I_D$ = 38.8 A | | 61 | 107 | nC |
| | | $V_{DS}$ = 15 V, $V_{GS}$ = 4.5 V, $I_D$ = 28.8 A | | 31.5 | 50 | |
| Gate-Source Charge | $Q_{gs}$ | | | 10 | | |
| Gate-Drain Charge | $Q_{gd}$ | | | 6 | | |
| Gate Resistance | $R_g$ | f = 1 MHz | | 1.4 | 2.1 | Ω |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD}$ = 15 V, $R_L$ = 0.625 Ω<br>$I_D$ ≅ 24 A, $V_{GEN}$ = 10 V, $R_g$ = 1 Ω | | 18 | 27 | ns |
| Rise Time | $t_r$ | | | 11 | 17 | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | 70 | 105 | |
| Fall Time | $t_f$ | | | 10 | 15 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD}$ = 15 V, $R_L$ = 0.67 Ω<br>$I_D$ ≅ 22.5 A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 Ω | | 55 | 83 | |
| Rise Time | $t_r$ | | | 180 | 270 | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | 55 | 83 | |
| Fall Time | $t_f$ | | | 12 | 18 | |
| **Drain-Source Body Diode Characteristics** | | | | | | |
| Continuous Source-Drain Diode Current | $I_S$ | $T_C$ = 25 °C | | | 120 | A |
| Pulse Diode Forward Current[a] | $I_{SM}$ | | | | 120 | |
| Body Diode Voltage | $V_{SD}$ | $I_S$ = 22 A | | 0.8 | 1.2 | V |
| Body Diode Reverse Recovery Time | $t_{rr}$ | $I_F$ = 20 A, di/dt = 100 A/µs, $T_J$ = 25 °C | | 52 | 78 | ns |
| Body Diode Reverse Recovery Charge | $Q_{rr}$ | | | 70.2 | 105 | nC |
| Reverse Recovery Fall Time | $t_a$ | | | 27 | | ns |
| Reverse Recovery Rise Time | $t_b$ | | | 25 | | |

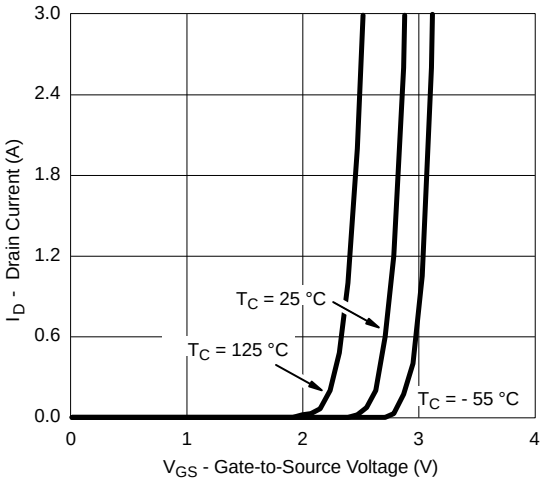
Notes:
a. Pulse test; pulse width ≤ 300 µs, duty cycle ≤ 2 %.
b. Guaranteed by design, not subject to production testing.

*Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*

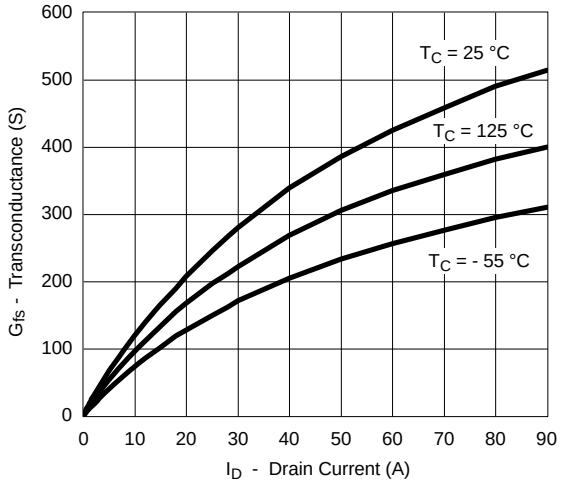
RATING AND CHARACTERISTIC CURVES (60N03)



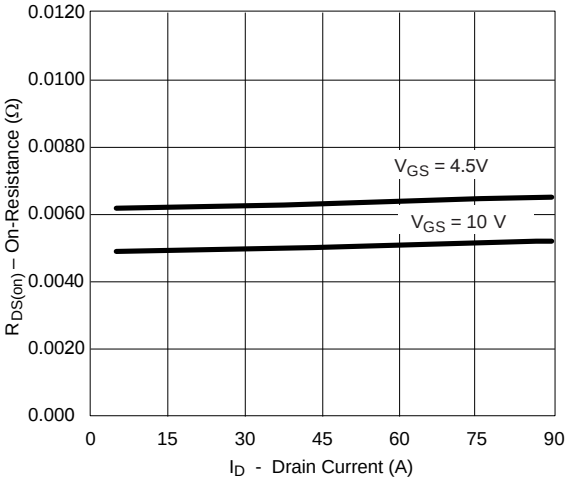

**Output Characteristics**



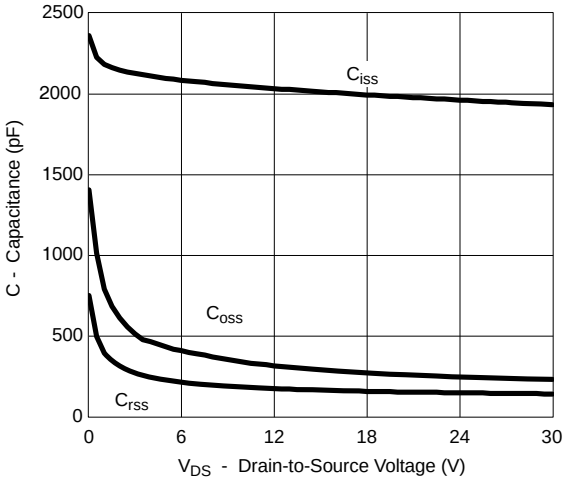

**Transfer Characteristics**



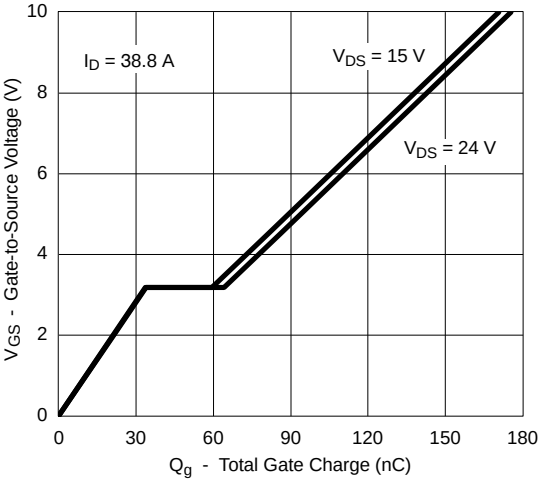

**Transconductance**




**$R_{DS(on)}$ vs. Drain Current**

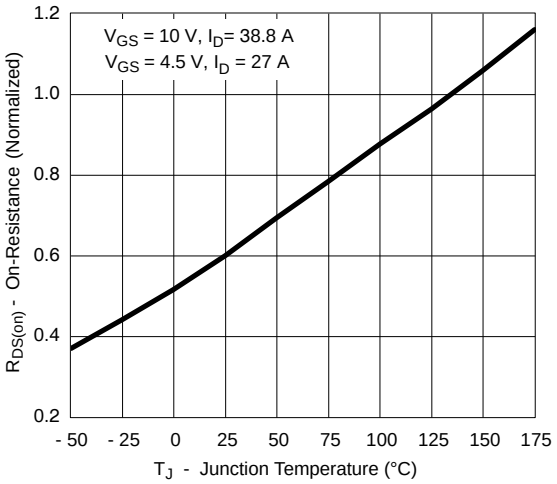



**Capacitance**

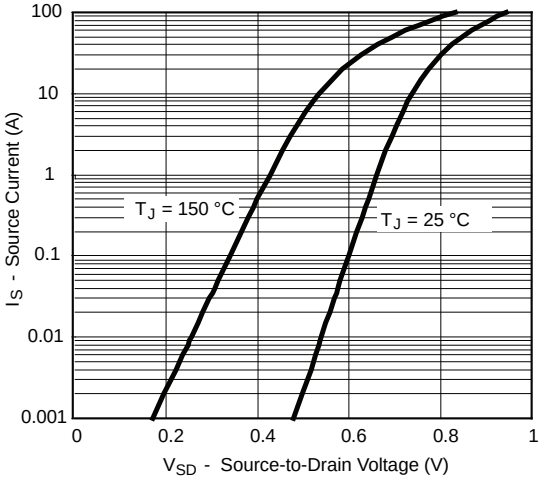



**Gate Charge**

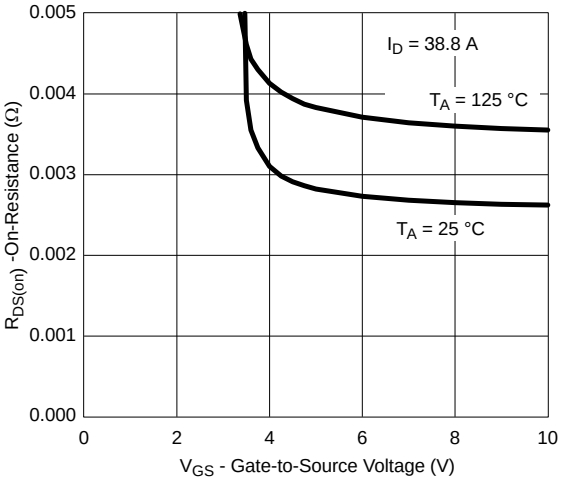
## RATING AND CHARACTERISTIC CURVES (60N03)



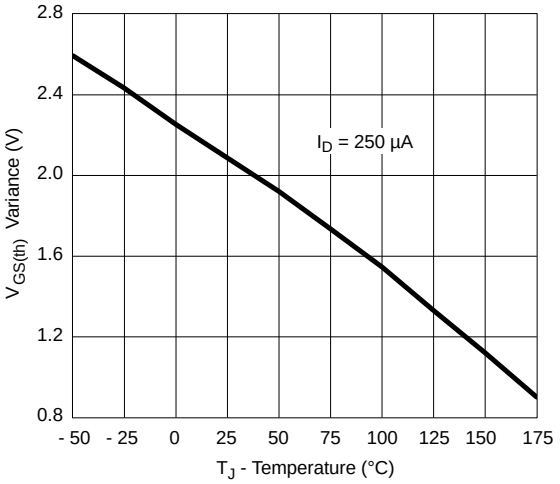

**On-Resistance vs. Junction Temperature**



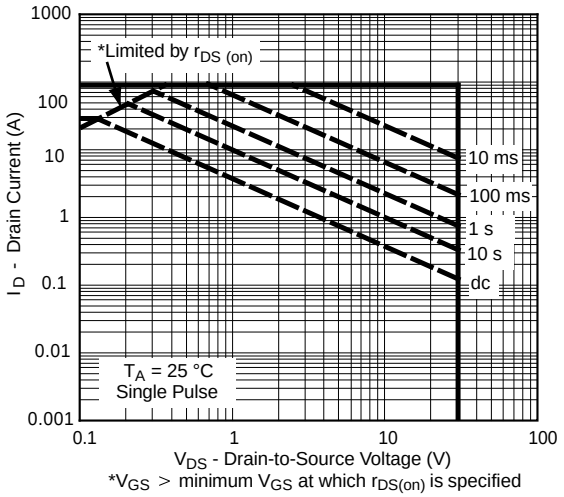

**Forward Diode Voltage vs. Temperature**




**$R_{DS(on)}$ vs. $V_{GS}$ vs. Temperature**

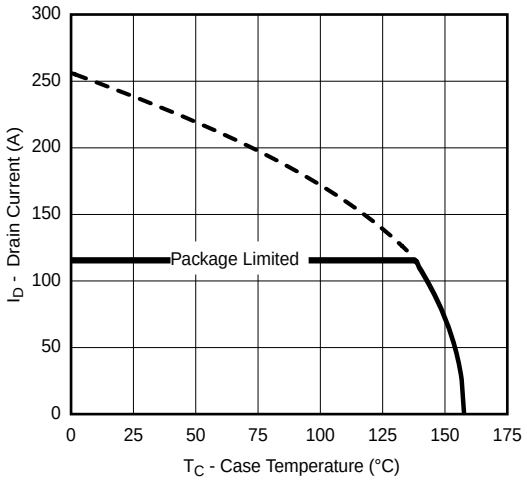



**Threshold Voltage**

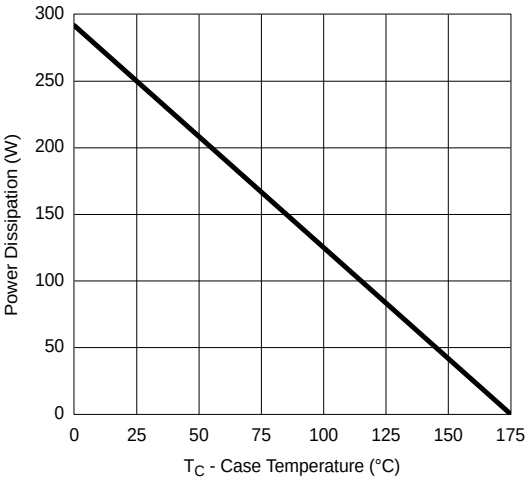



**Safe Operating Area, Junction-to-Ambient**

## RATING AND CHARACTERISTIC CURVES (60N03)

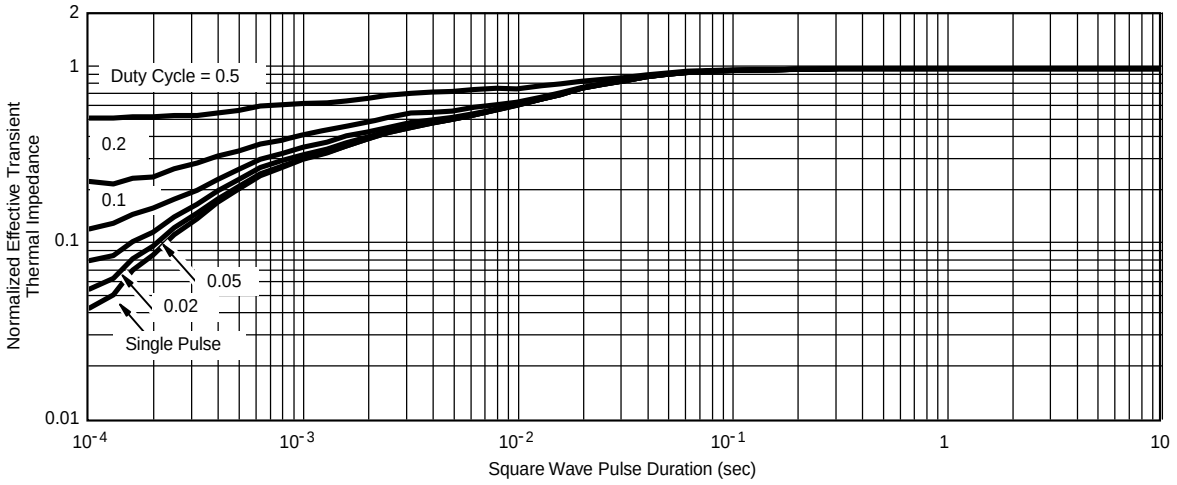



**Current Derating***




**Power Derating**

*The power dissipation $P_D$ is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.




**Normalized Thermal Transient Impedance, Junction-to-Case**